

Pantograph testing for simulation models

TTI SECTOR PLENARY MEETING
MÁLAGA 2025

P. Antunes, A. Collina, M. Tur

University of
HUDDERSFIELD
Institute of Railway Research

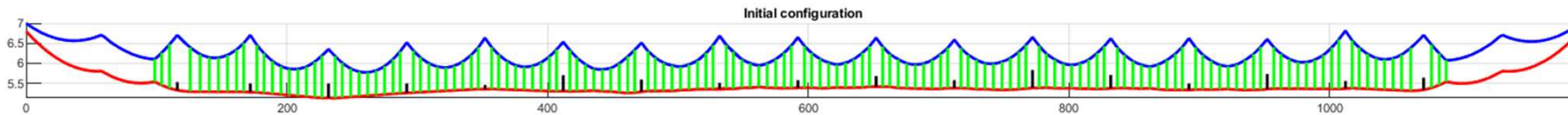
 **POLITECNICO
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Department of
Mechanical Engineering

 **UNIVERSITAT
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Outline

1. Simulation of overhead contact line
2. Pantograph models
3. Test bench
4. Pantograph testing
 - Harmonic functions
 - Limitations: Non-linear response
5. Testing for simulation
 - Guidelines for choosing the model & test for each application
6. HiL testing

1. Simulation of OHL

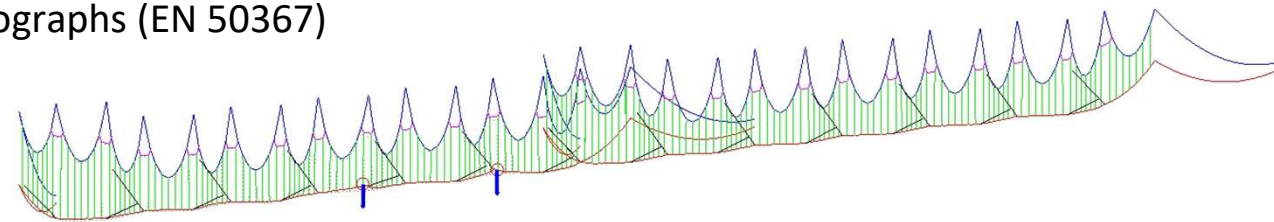


- Numerical simulations are becoming increasingly important in the transport sector

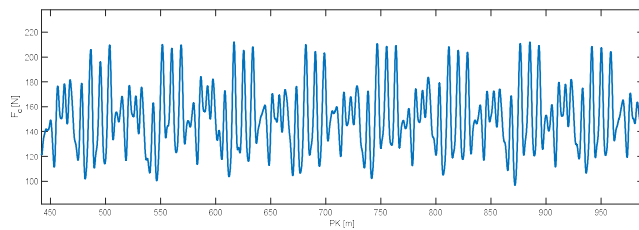
- Ensure operational safety
- Used for homologation of new lines / pantographs (EN 50367)

Conformity assessment

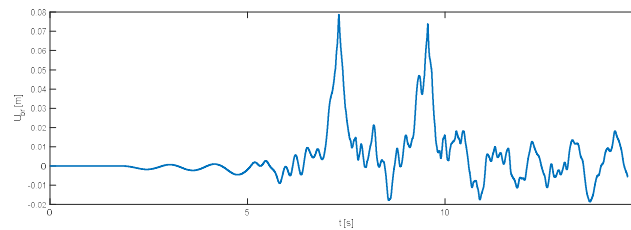
- Deliver results for designing new lines:



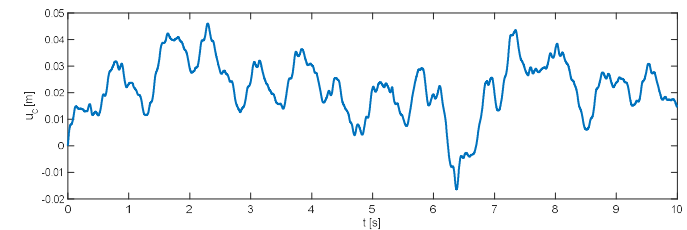
Contact force



Steady arm elevation



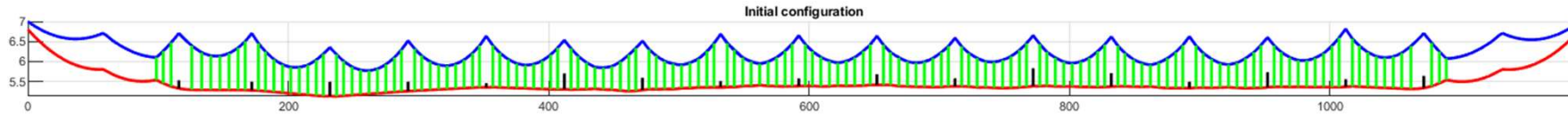
Contact point height



- Long-term goal:

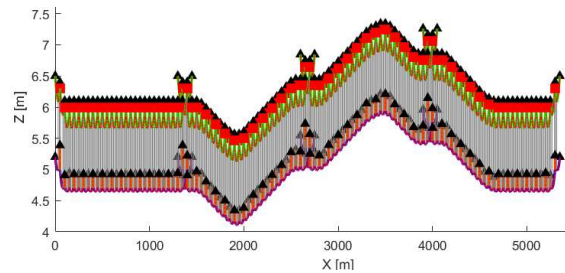
- Virtual homologation: replace on-track tests with numerical simulations as much as possible
- Maintain the same level of safety and reliability
- Resilience: system response under extreme or unexpected events

1. Simulation of OHL

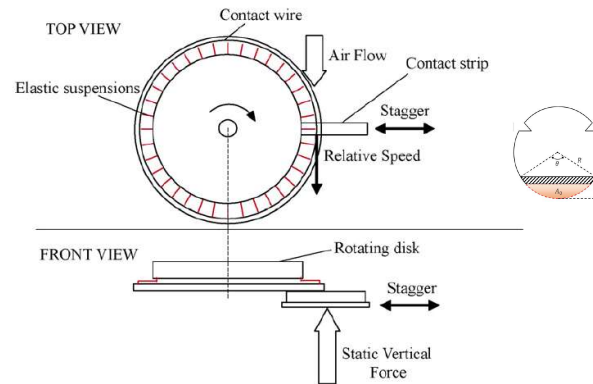


- Advanced simulations in Research Institutes

Catenary with gradient 1:625



Wear prediction using simulation results

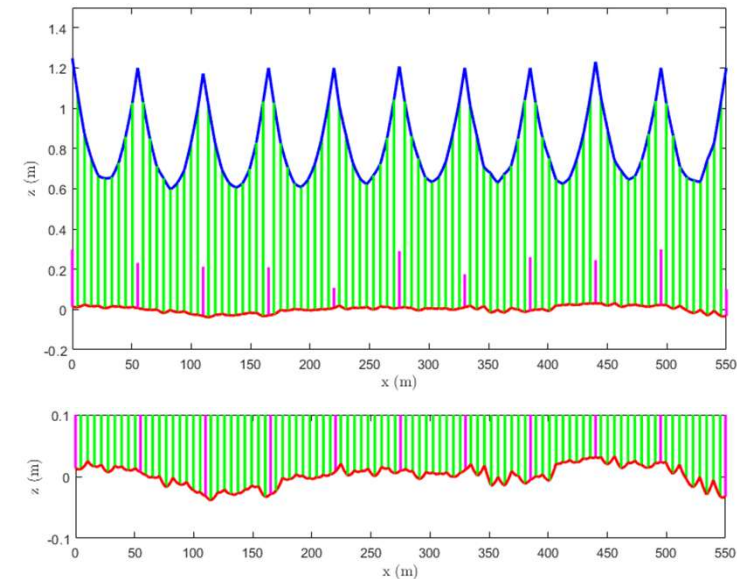


$$NWR = k_1 \left(\frac{1}{2} \left(1 + \frac{I_c}{I_0} \right) \right)^{-\alpha} \left(\frac{F_c}{F_0} \right)^\beta \frac{F_c}{H} + k_2 \frac{R_c I_c^2}{H v} (1 - u) + k_3 \frac{V_a I_c}{v H_m \rho} u$$

Mechanical Wear

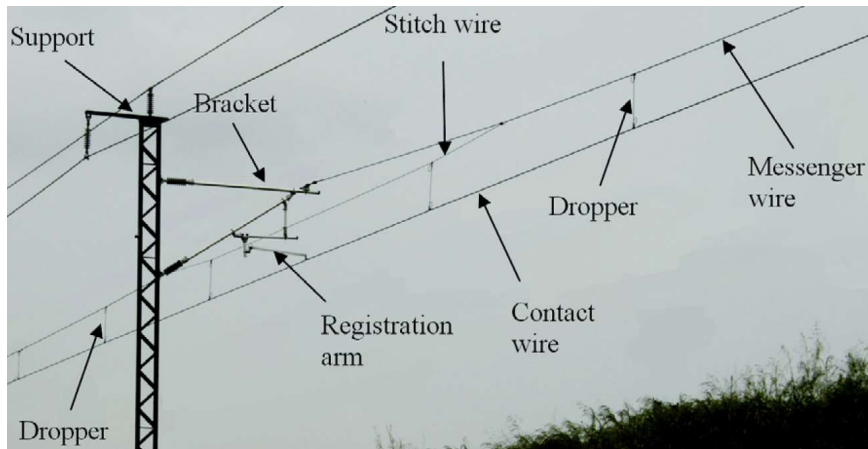
Electric Wear

Fast simulation: Parametric analysis and geometric optimization



1. Simulation of OHL - Components

- Catenary model
 - Designed geometry: dropper length, bracket position
 - Material properties: Young modulus, damping,
 - Cable properties: inertia, section, ...
 - Tensioning devices



Structural components:

- Masts and supports
- Registration and steady arms
- Brackets

Cables:

- Messenger wire
- Contact wire
- Droppers
- Stitch wire

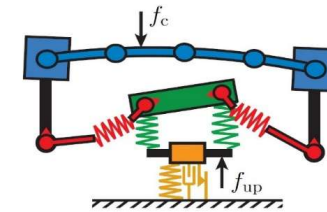
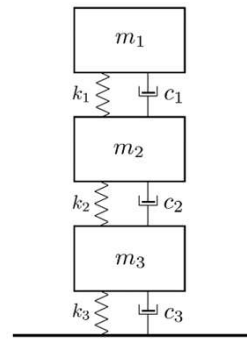
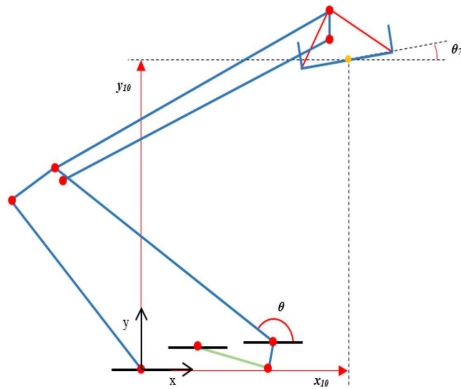
- Simulation code & user parameters
 - Algorithm parameters: time increment, ...
 - Load cases to be solved: speed of the vehicle, number of pantographs, ...
 - Regulation: EN 50318
 - International benchmark

• Pantograph model



- Noticeable influence on the results
- Important to have affordable models
- How tune models with lab test

2. Pantograph model - Multibody . Lumped mass . Improved lumped



2. Pantograph model - Multibody . Lumped mass . Improved lumped

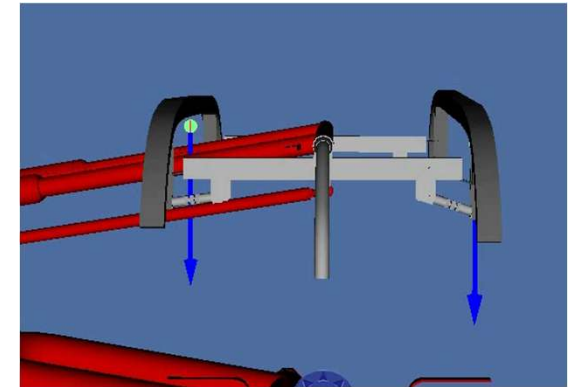
Physical Pantograph:



CAD Model:

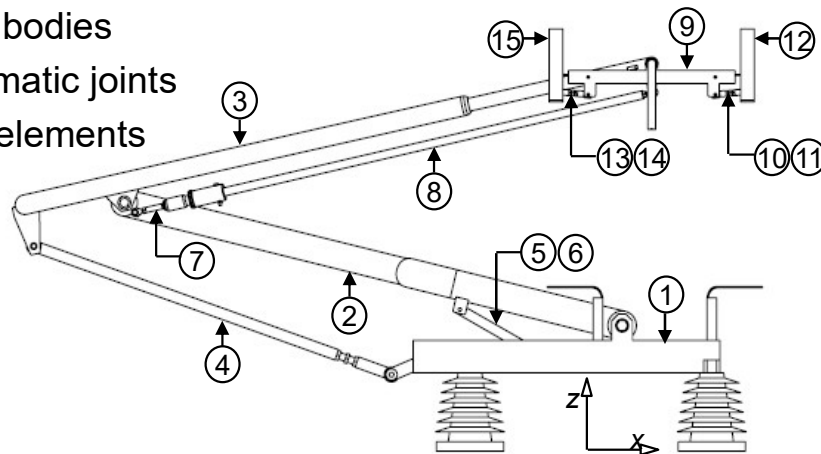


Multibody Model Animation:

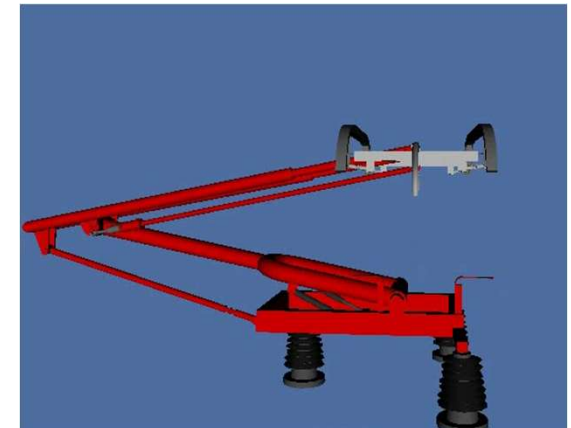


Multibody Model:

- 15 rigid bodies
- 22 kinematic joints
- 7 force elements



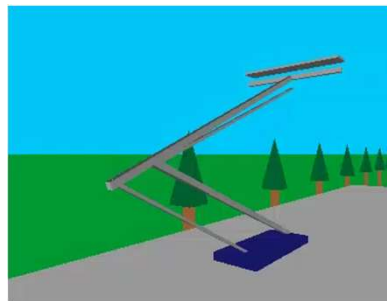
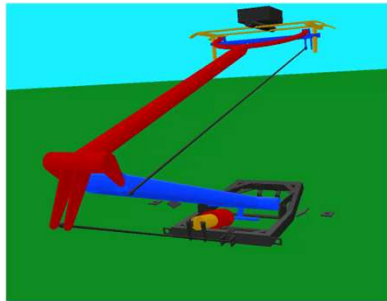
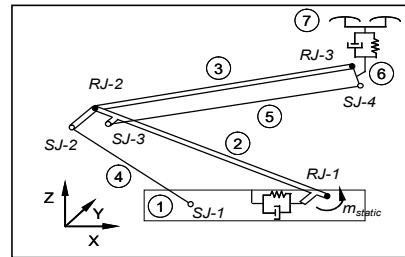
ID	Rigid Body	Mass [kg]
1	Base	34.86
2	Lower Arm	31.20
3	Upper Arm	22.61
4	Lower Link	3.216
5	Sp. Damper L.	0.862
6	Sp. Damper H.	2.094
7	Upper Link L.	0.939
8	Upper Link H.	3.233
9	Stabilization Arm	7.177
10	Head Link 1	0.377
11	Head Link 2	0.377
12	C. Strip Front	4.939
13	Head Link 3	0.377
14	Head Link 4	0.377
15	C. Strip Back	4.939



2. Pantograph model - Multibody . Lumped mass . Improved lumped



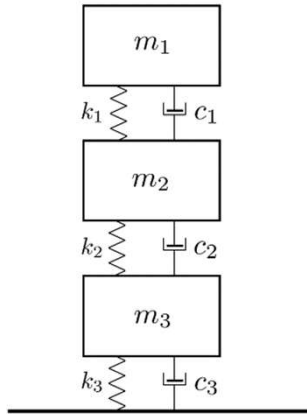
Technical Design Data



Testing can be used for validation

- Pros & cons
 - + Build from design information
 - + Only technical data is required. No laboratory tests
 - + Model parameters have direct correspondence to the physical pantograph, allowing design optimization studies
 - + Can be used for new pantograph design
 - + Allow to study pantograph-catenary interaction in more complex and realistic environments: Curves on track and non linear aerodynamic effects
- Difficult parameter tuning
- Information not always available
- It is non-linear
- Complex components: joint, spring, damper, ...

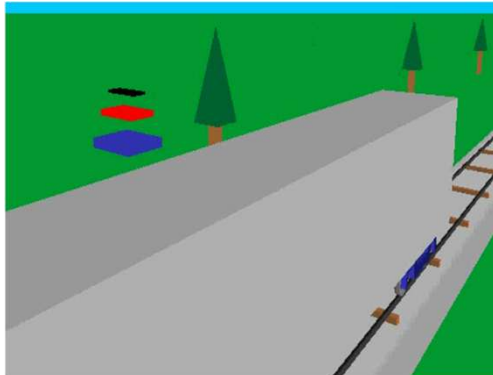
2. Pantograph model - Multibody . Lumped mass . Improved lumped



- Pros & cons
 - + Simple, dynamic equations well known
 - + Fast simulation
 - + Low number of parameters: m_1 , m_2 , m_3 , c_1 , c_2 , c_3 , k_1 , k_2 , k_3
 - + Most used – accepted by all

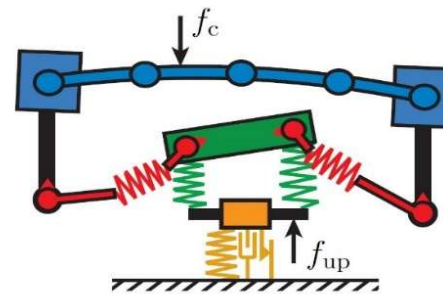
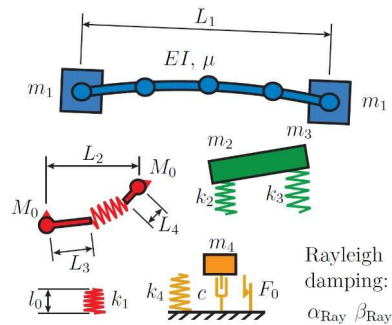
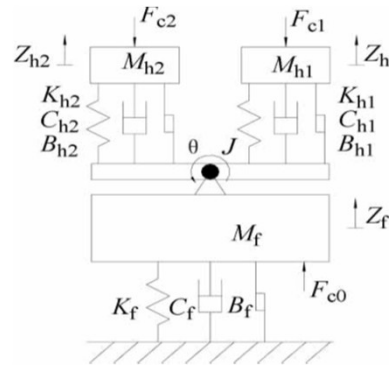
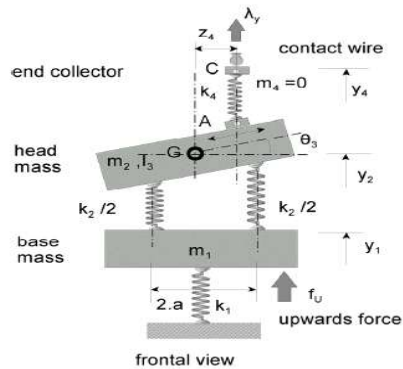
> Linear model

- Parameter estimation
- Limitations in some cases
- No correspondence to the real pantograph components (don't allow design optimization)



Need testing for parameter tuning and validation

2. Pantograph model - Multibody . Lumped mass . Improved lumped



• Pros & cons

- + Add complexity: 2D/3D, friction, strips deformation
- + Better fitting of the real behaviour
- More difficult parameter estimation
- More complex to compute

Need testing for tuning and validation

3. Test bench

Vertical and horizontal actuators: Impose displacement of the contact strips

Contact force measurement

Pantograph

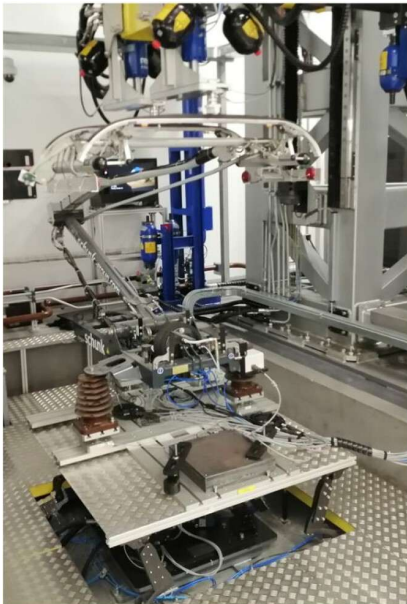
Other sensors:

- Acceleration
- Pressure
- Displacement



3. Test bench

Institute of Railway Research



POLIMI



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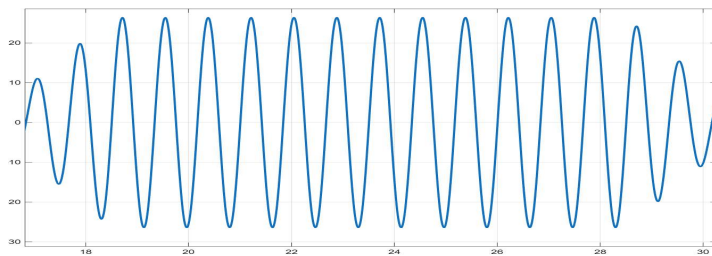


Different actuation and control technology

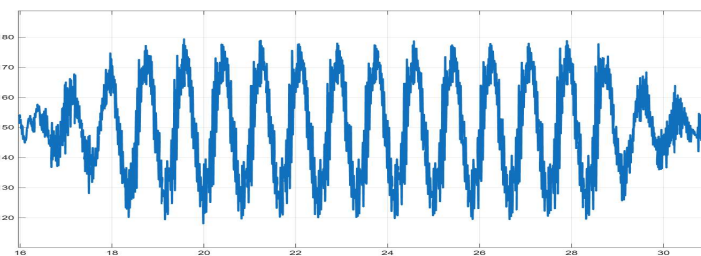
4. Pantograph testing

- Harmonic excitation
 - Frequency response function (Frf)

Displacement amplitude (U)

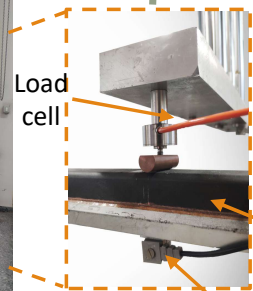


Contact force amplitude (F)



Actuator

Pantograph

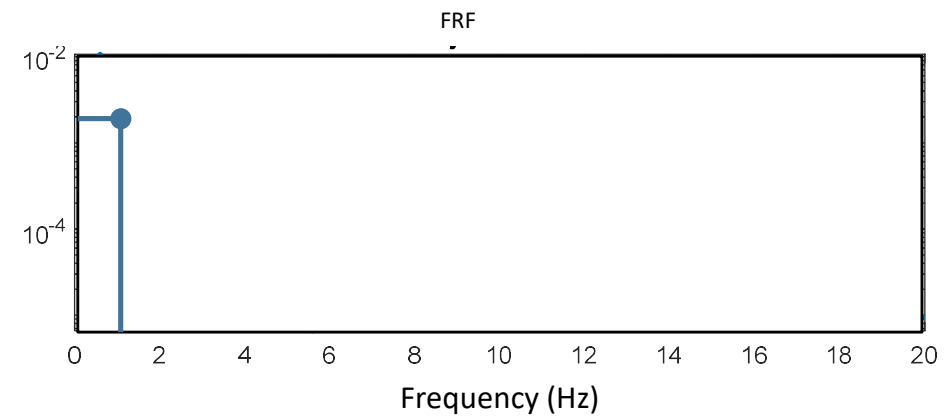


Load cell

Contact Strip

Accelerometer

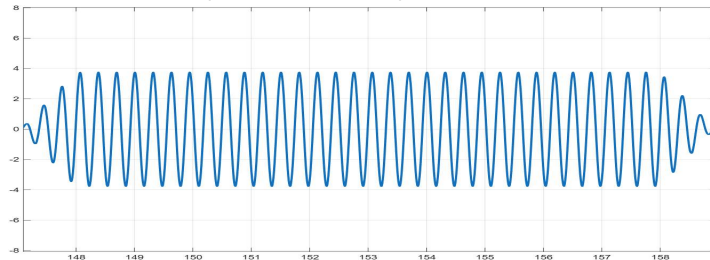
$$Frf = \frac{U}{F}$$



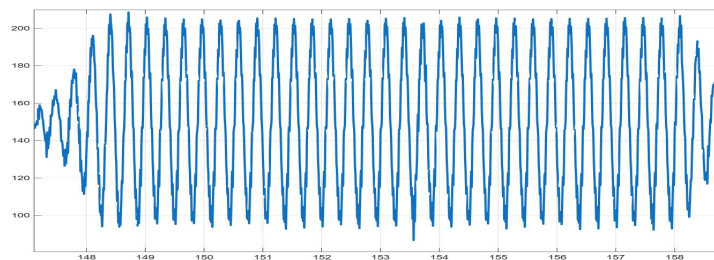
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- Harmonic excitation
 - Frequency response function (Frf)

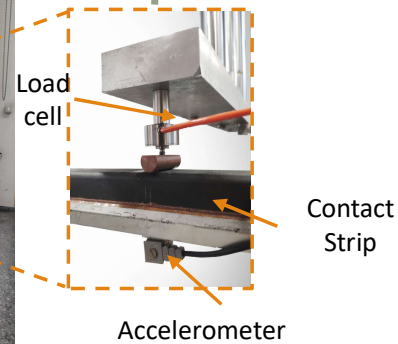
Displacement amplitude (U)



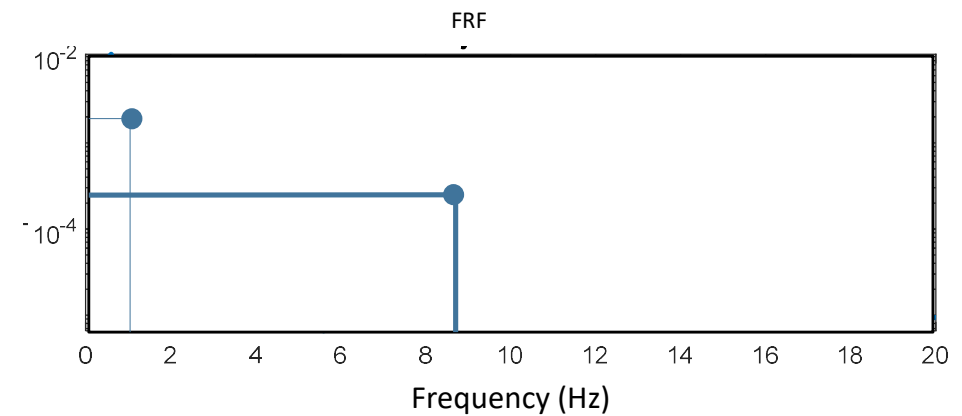
Contact force amplitude (F)



Pantograph



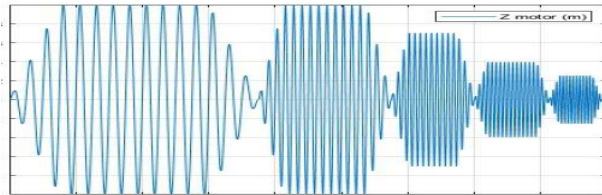
$$Frf = \frac{U}{F}$$



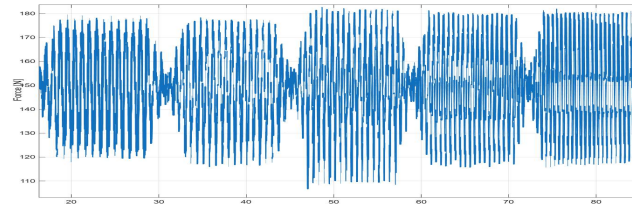
4. Pantograph testing

- Harmonic excitation
 - Frequency response function (Frf)

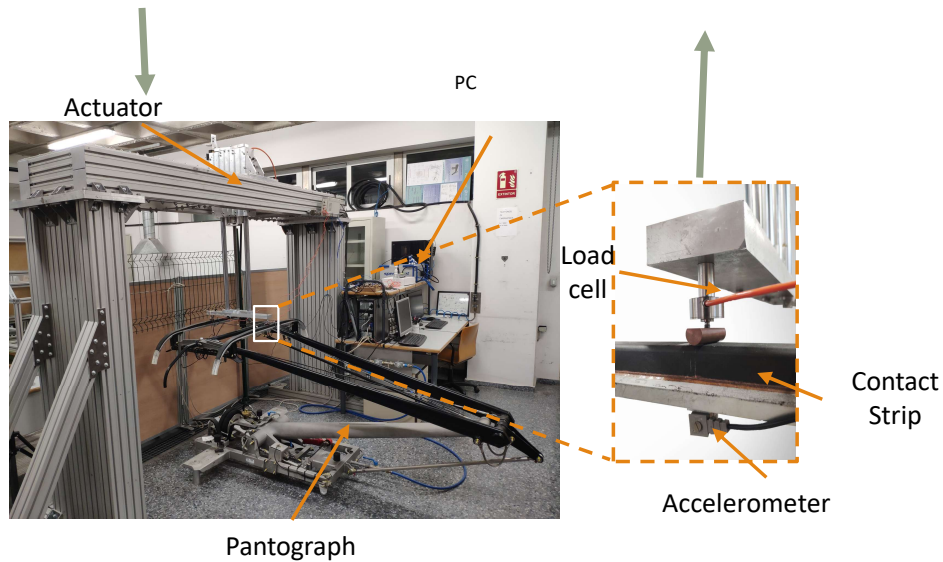
Displacement (U)



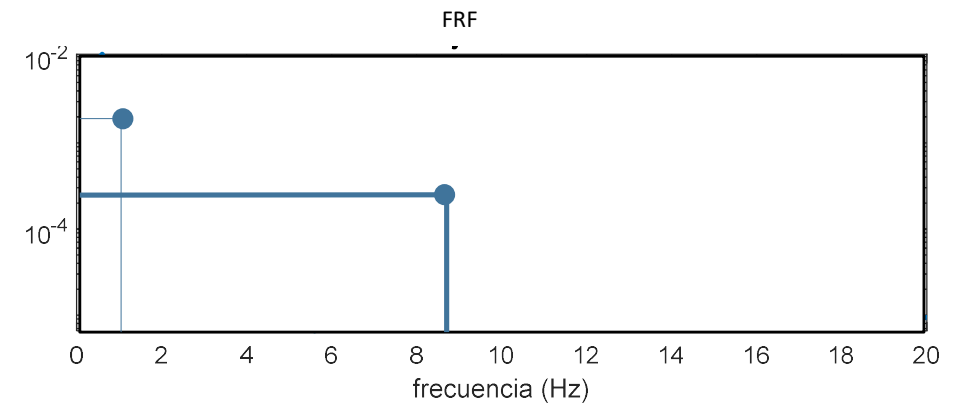
Contact force (F)



Used for tuning parameters
and validation



$$Frf = \frac{U}{F}$$

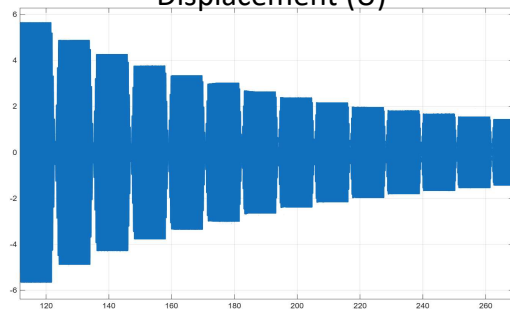


4. Pantograph testing

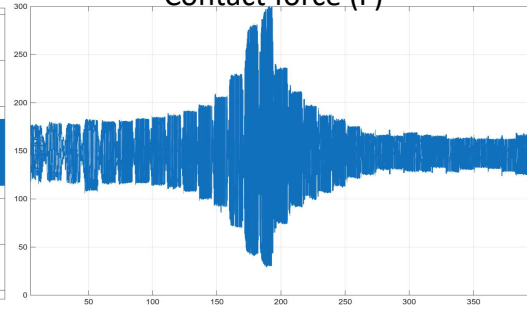
- Other excitation signals
 - Frequency response function (Frf)

Slow sine sweep

Displacement (U)

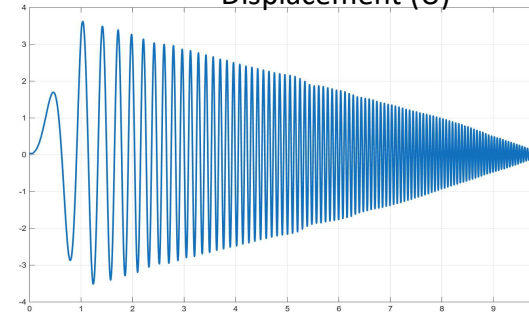


Contact force (F)

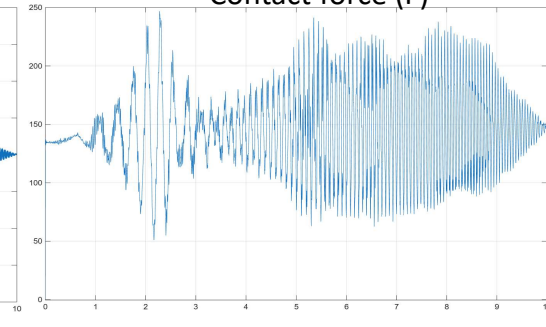


Chirp

Displacement (U)

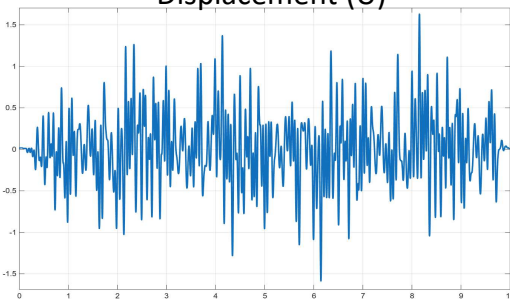


Contact force (F)

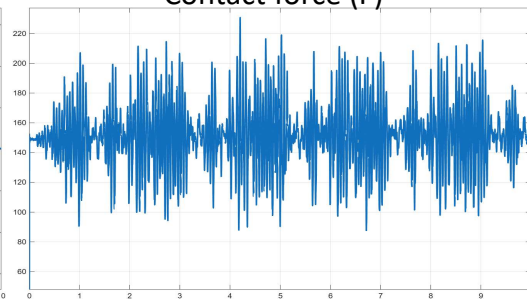


Pseudo random

Displacement (U)

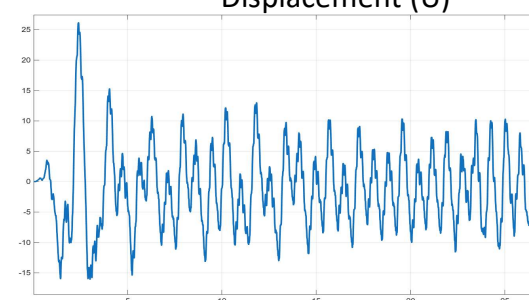


Contact force (F)

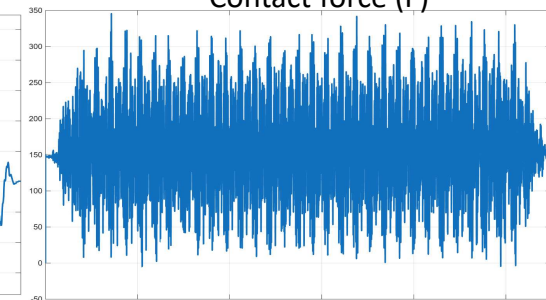


Pantograph-catenary interaction

Displacement (U)

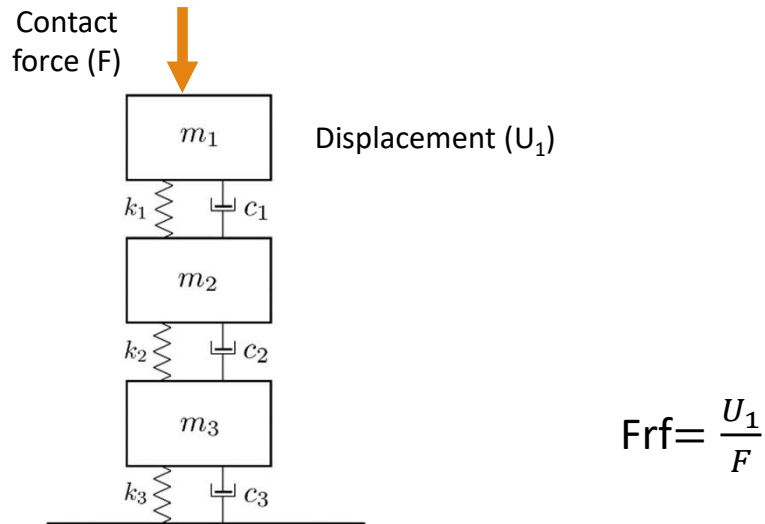


Contact force (F)

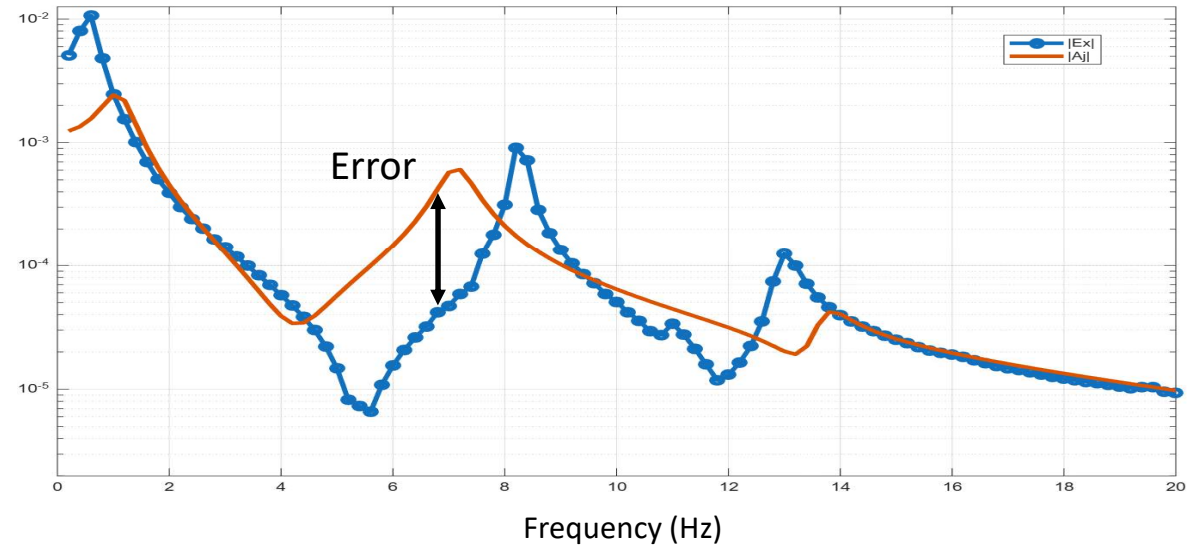


4. Pantograph testing

- Model fitting
 - Frequency response function (Frf)

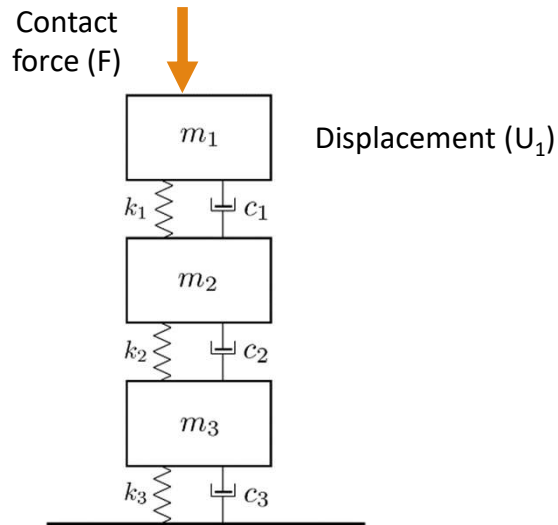


$$\left(-\omega^2 \begin{bmatrix} m_1 & 0 & 0 \\ 0 & m_2 & 0 \\ 0 & 0 & m_3 \end{bmatrix} + j\omega \begin{bmatrix} c_1 & -c_1 & 0 \\ -c_1 & c_1 + c_2 & -c_2 \\ 0 & -c_2 & c_2 + c_3 \end{bmatrix} + \begin{bmatrix} k_1 & -k_1 & 0 \\ -k_1 & k_1 + k_2 & -k_2 \\ 0 & -k_2 & k_2 + k_3 \end{bmatrix} \right) \begin{Bmatrix} U_1 \\ U_2 \\ U_3 \end{Bmatrix} = \begin{Bmatrix} F_c \\ 0 \\ F_0 \end{Bmatrix}$$



4. Pantograph testing

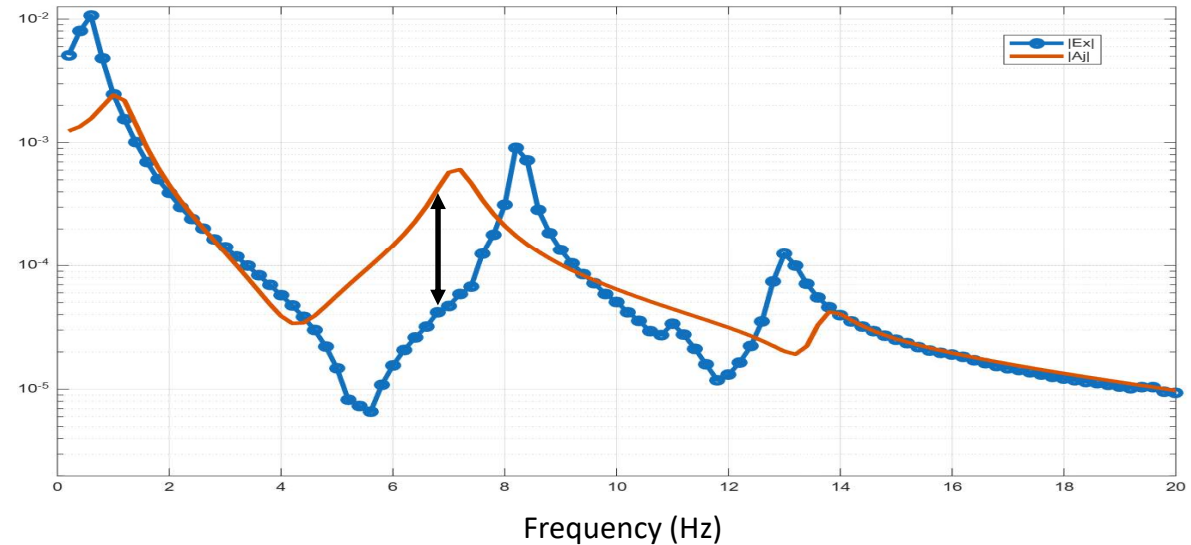
- Model fitting
 - Frequency response function (Frf)



$$Frf = \frac{U_1}{F}$$

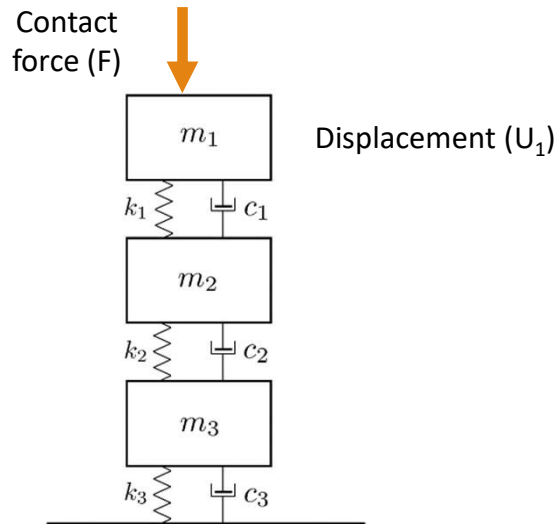
$$\left(-\omega^2 \begin{bmatrix} m_1 & 0 & 0 \\ 0 & m_2 & 0 \\ 0 & 0 & m_3 \end{bmatrix} + j\omega \begin{bmatrix} c_1 & -c_1 & 0 \\ -c_1 & c_1 + c_2 & -c_2 \\ 0 & -c_2 & c_2 + c_3 \end{bmatrix} + \begin{bmatrix} k_1 & -k_1 & 0 \\ -k_1 & k_1 + k_2 & -k_2 \\ 0 & -k_2 & k_2 + k_3 \end{bmatrix} \right) \begin{Bmatrix} U_1 \\ U_2 \\ U_3 \end{Bmatrix} = \begin{Bmatrix} F_c \\ 0 \\ F_0 \end{Bmatrix}$$

$$Error = \sum_{i=1}^{Np} (Frf_{test}(\omega_i) - Frf_{model}(\omega_i))^2$$



4. Pantograph testing

- Model fitting
 - Frequency response function (Frf)

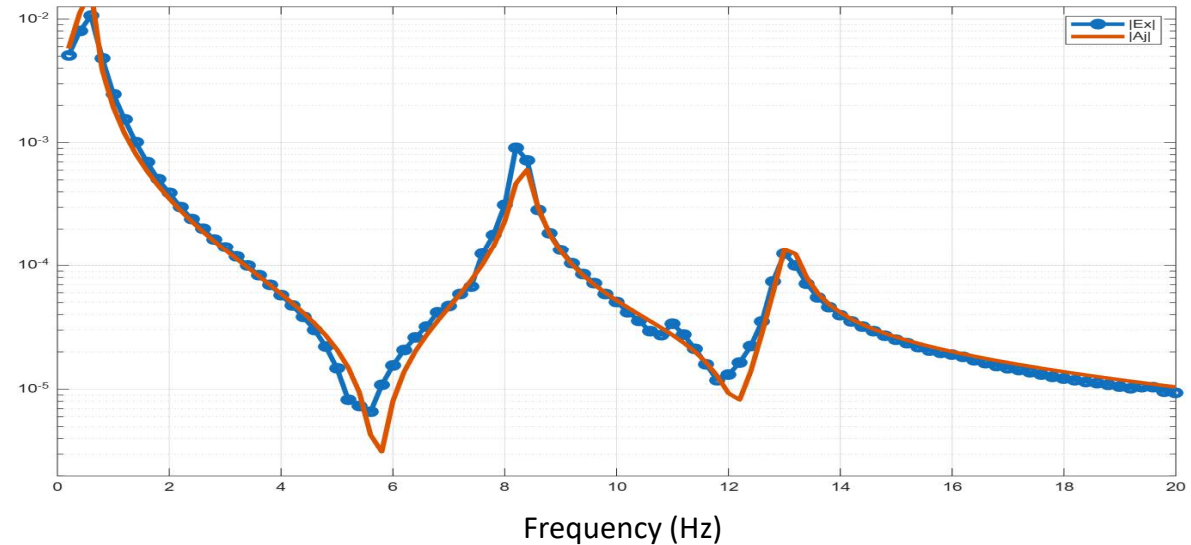


$$\text{Frf} = \frac{U_1}{F}$$

$$\left(-\omega^2 \begin{bmatrix} m_1 & 0 & 0 \\ 0 & m_2 & 0 \\ 0 & 0 & m_3 \end{bmatrix} + j\omega \begin{bmatrix} c_1 & -c_1 & 0 \\ -c_1 & c_1 + c_2 & -c_2 \\ 0 & -c_2 & c_2 + c_3 \end{bmatrix} + \begin{bmatrix} k_1 & -k_1 & 0 \\ -k_1 & k_1 + k_2 & -k_2 \\ 0 & -k_2 & k_2 + k_3 \end{bmatrix} \right) \begin{Bmatrix} U_1 \\ U_2 \\ U_3 \end{Bmatrix} = \begin{Bmatrix} F_c \\ 0 \\ F_0 \end{Bmatrix}$$

$$\text{Error} = \sum_{i=1}^{Np} W_i \left(\text{Frf}_{\text{test}}(\omega_i) - \text{Frf}_{\text{model}}(\omega_i) \right)^2$$

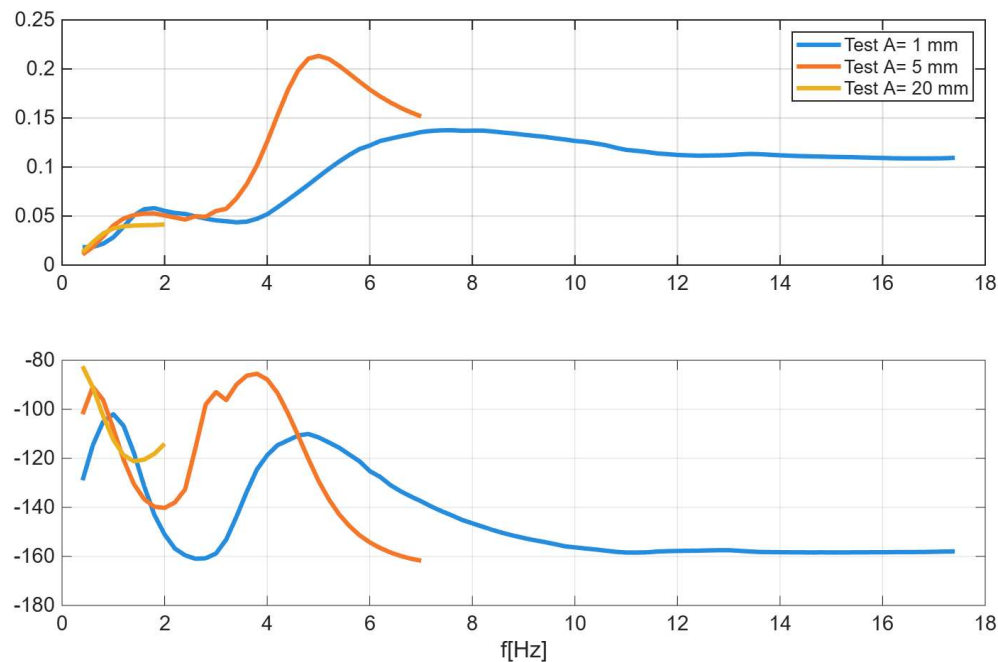
Weighted error



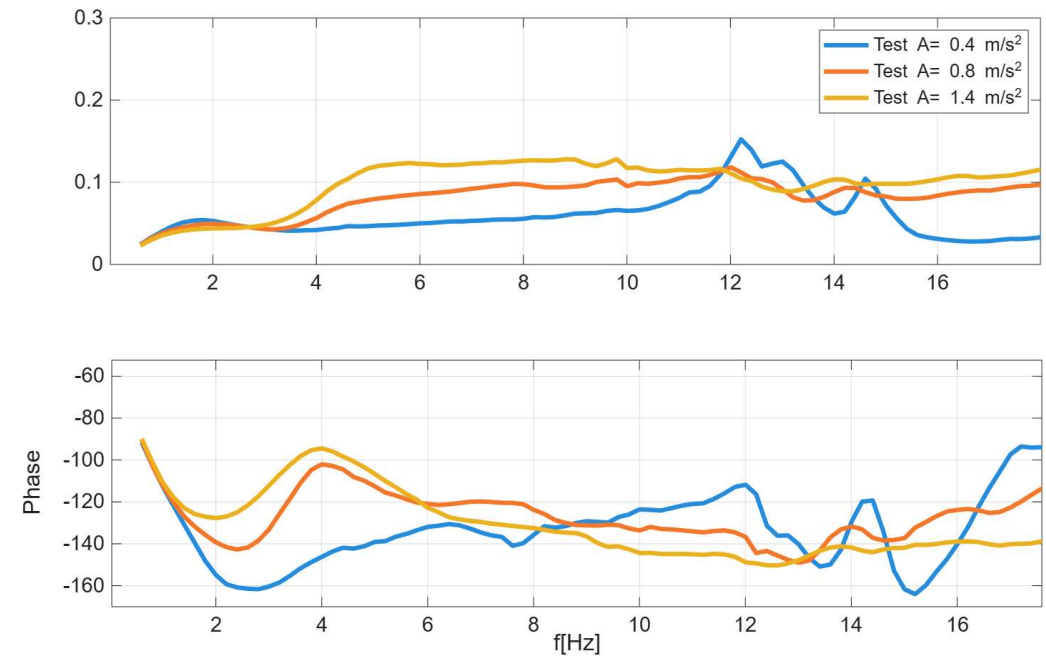
4. Pantograph testing

- Limitations
 - Variation of the Frf with amplitude of the input
 - Pneumatic system, Non-linear springs, joint friction

Acceleration Frf (Pantograph 1)



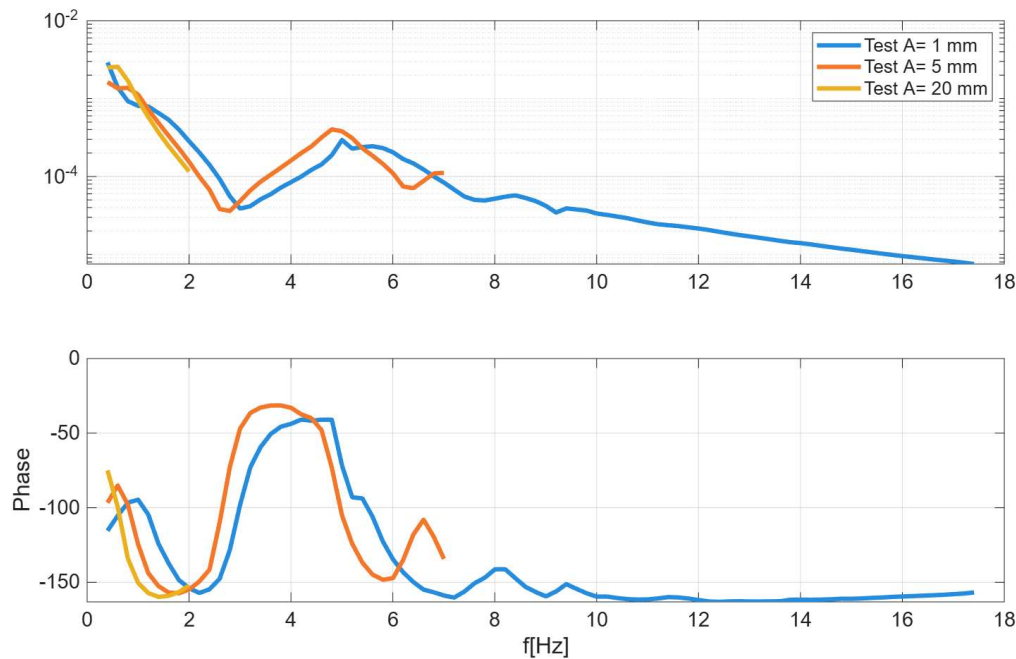
Acceleration Frf (Pantograph 1)



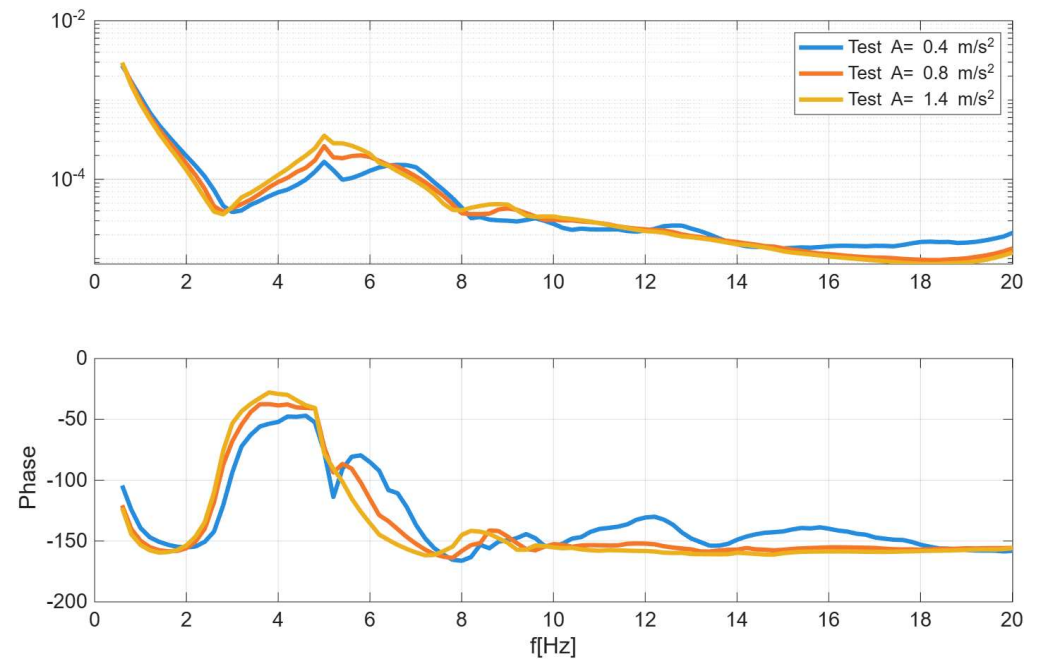
4. Pantograph testing

- Limitations
 - Variation of the Frf with amplitude of the input
 - Pneumatic system, Non-linear springs, joint friction

Displacement Frf (Pantograph 2)



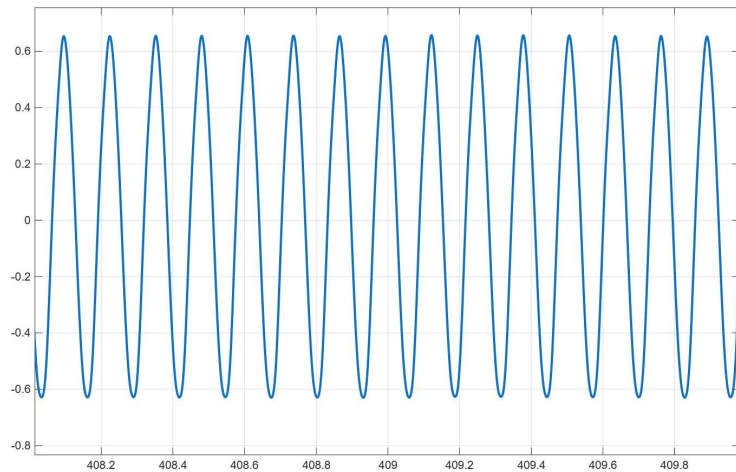
Displacement Frf (Pantograph 2)



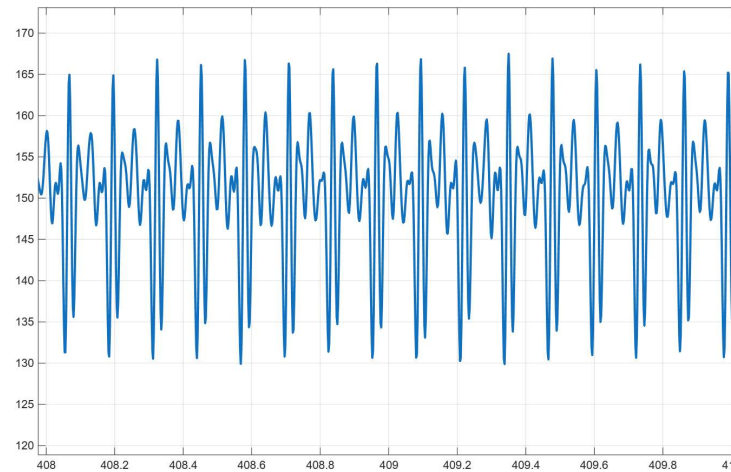
4. Pantograph testing

- Limitations (Non-linear response)
 - Sinusoidal displacement $\rightarrow$ Non-sinusoidal force
 - Influence of mean pantograph height
 - Influence of mean contact force

Displacement (Z)

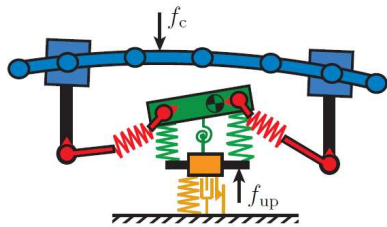


Contact force (F)



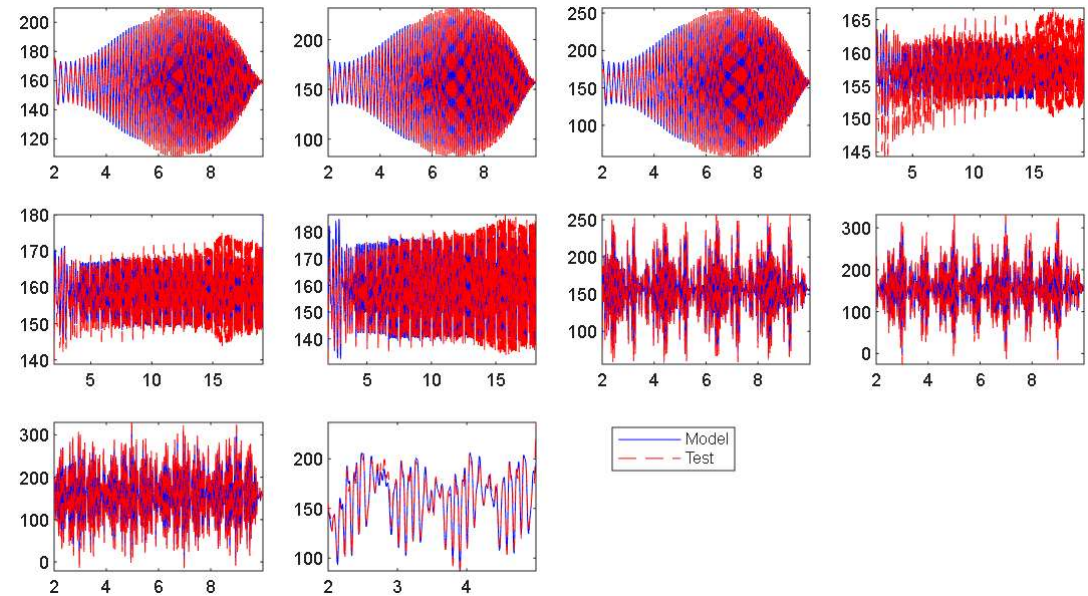
4. Pantograph testing

- Fitting with advanced models
 - **Time domain** vs frequency domain
 - 19 parameters (Genetic Algorithm)

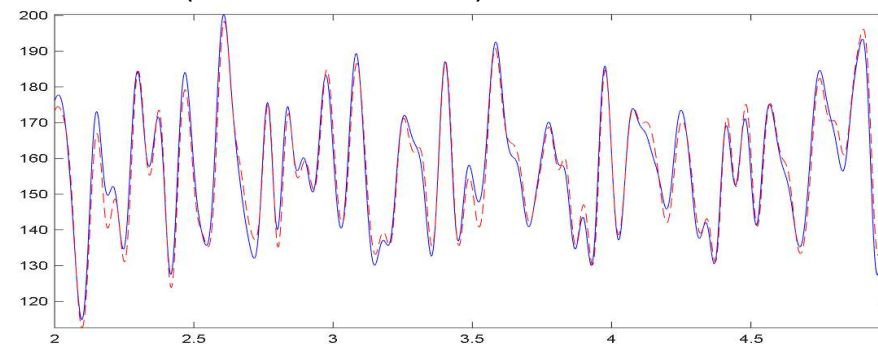


- Flexibility of the contact strips
- Rotational friction of the collector head suspension springs
- Rotation of contact strips and pantograph upper frame
- Validation up to 60 Hz

Training data



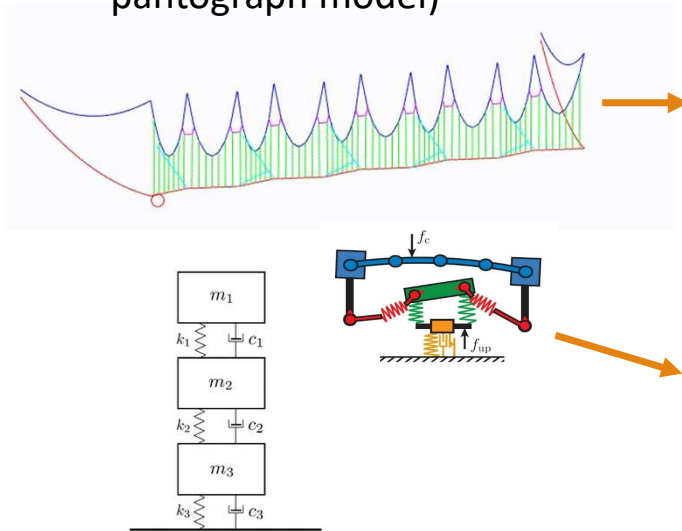
Validation (Contact force vs time)



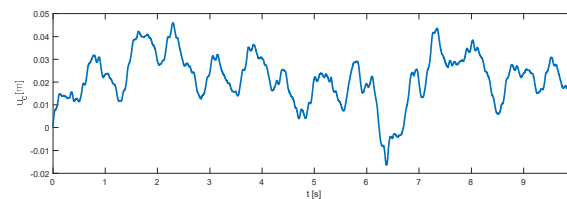
5. Testing for simulation models

- IDEA: Depending on the problem (type of catenary, speed, pantograph) a suitable pantograph model should be used
 - The simplest model that provide acceptable accuracy
 - Guidelines for pantograph testing methods to build models

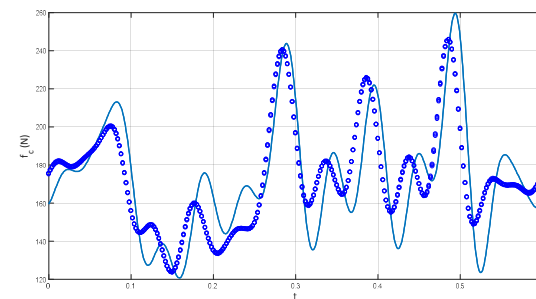
Simulation (chosen pantograph model)



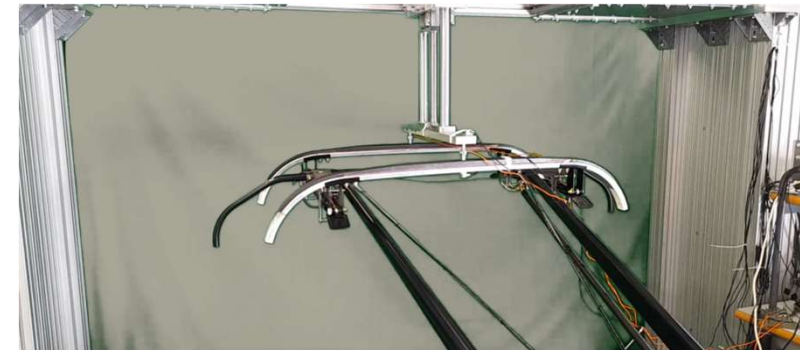
Contact wire height



Contact force (simulation and test)

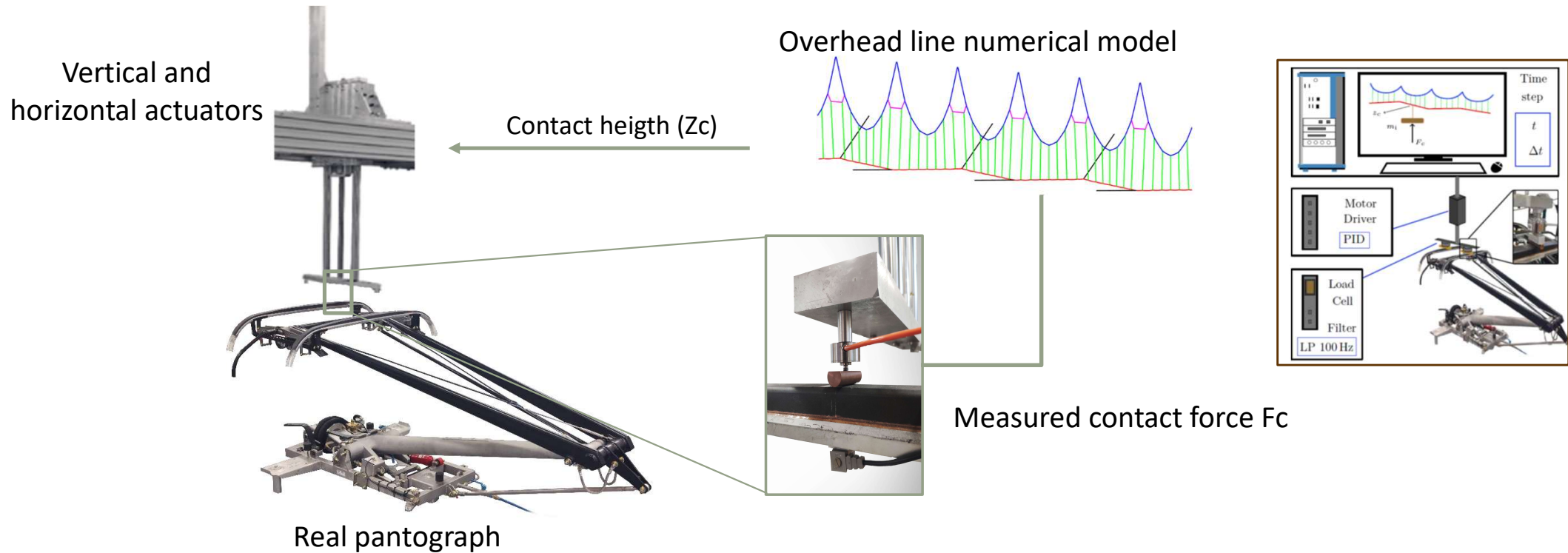


Test rig



6. Hardware-in-the-Loop

- HiL is a compromise between pure numerical simulation and on-track tests



- In the HiL test, the real pantograph interacts with a simulated OCL.
 - Tests can be carried out both in real time and off-line.
 - Experiences in this field have been already given by different research teams using different technologies

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